



Overview

General:

The JSX-3400R is JEOL's most advanced energy dispersive fluorescent X-ray analyzer. It supports element screening compliant to RoHS and ELV directives as well as high sensitivity photo X-ray analysis of general samples.

Features:

1. Speedy high sensitivity trace analysis
 - o New optic system and high resolution Si (Li) semiconductor detector
 - o Latest X-ray filter for RoHS specifications

Absorbs stray and continuous X-rays from the X-ray bulb that interfere with spectral data, reducing background to enhance detection efficiency.

2. Standard calibration curves for plastic and metals, making it unnecessary for the user to create calibration curves
 - o Calibration software and samples incorporated for longer use of

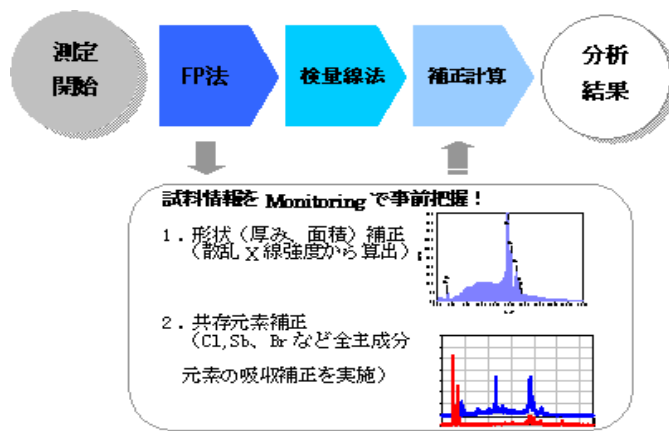
calibration curves; easy routine maintenance

3. Simple operation

- Single key clicks for complete analysis

4. Preliminary identification of samples (size and major components) by Monitoring

- Automatically identifies the morphology (thickness, area) and type of a sample to correct its effect on analysis, enhancing reliability of



analytical results

5. Large specimen chamber (300 mm diameter)

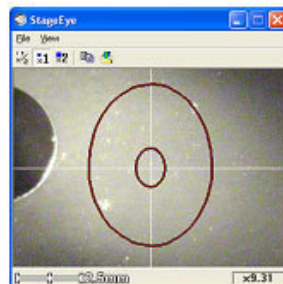
- Accommodates large samples as a whole



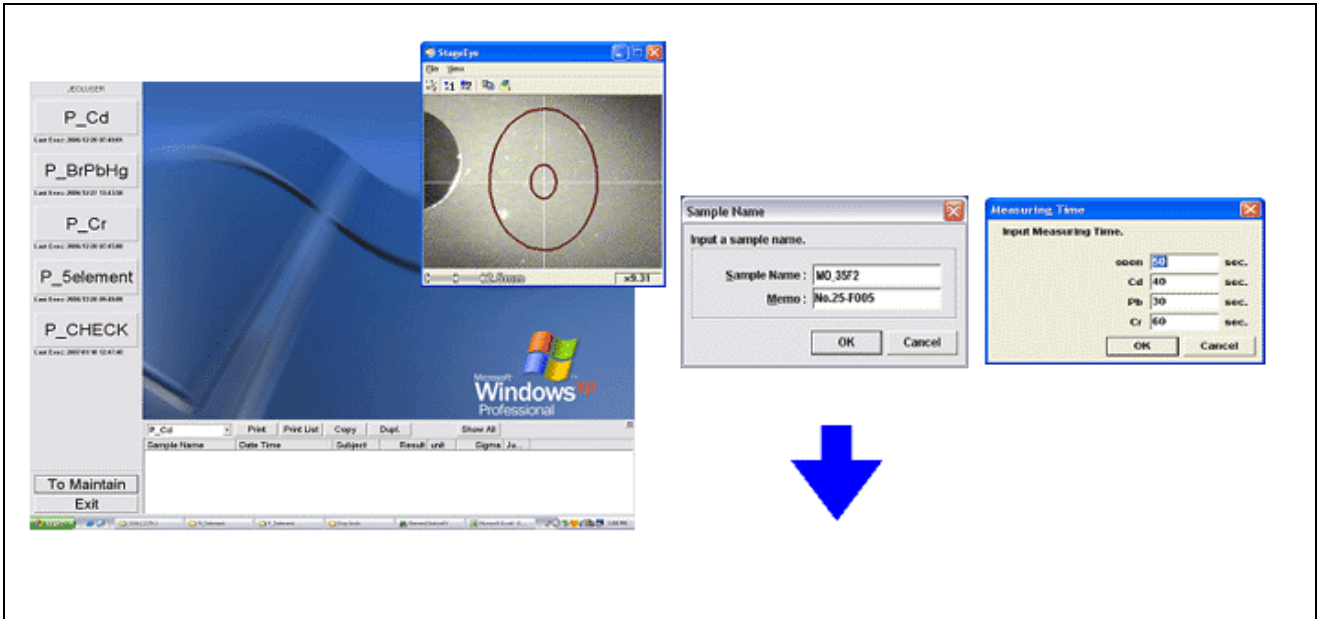


Easy operation

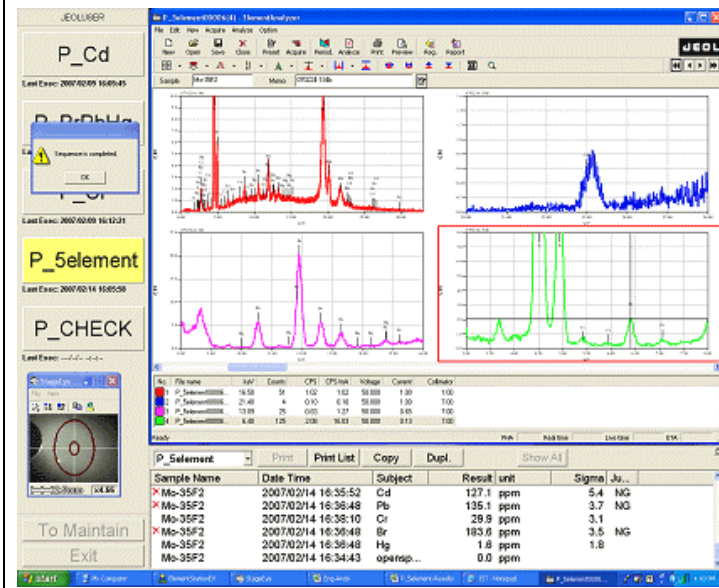
Load a sample onto the specimen stub. Position the sample while observing CCD camera images.



Select Plastic [5 components], and enter the sample name and measurement time. Click OK, and the system begins analysis.



End of analysis. The system automatically saves the data in file.



Sample No.	Date Time	Subject	Result	unit	Sigma	Judge	
2	2/14/2007 15:31	Cd	3	ppm	2.9		C:\Documents\jeo\CdD3_2.cib
3	2/14/2007 15:32	Pb	13.2	ppm	2.5		C:\Documents\jeo\PbD3_2.cib
4	2/14/2007 15:33	Cr	18.5	ppm	8.8		C:\Documents\jeo\CrD3_2.cib
5	2/14/2007 15:32	Br	3.9	ppm	0.8		C:\Documents\jeo\BrD3_2.cib
6	2/14/2007 15:32	Hg	6.2	ppm	3.9	NG	C:\Documents\jeo\HgD3_2.cib
7	2/14/2007 15:29	openspect	0	ppm			C:\Documents and Settings\UEO
8	2/14/2007 15:44	Cd	134.4	ppm	5.1	NG	C:\Documents\jeo\CdD3_2.cib
9	2/14/2007 15:45	Pb	135.5	ppm	3.9	NG	C:\Documents\jeo\PbD3_2.cib
10	2/14/2007 15:47	Cr	33.1	ppm	3.2		C:\Documents\jeo\CrD3_2.cib
11	2/14/2007 15:45	Br	182.5	ppm	3.6		C:\Documents\jeo\BrD3_2.cib
12	2/14/2007 15:45	Hg	2.6	ppm	1.9		C:\Documents\jeo\HgD3_2.cib
13	2/14/2007 15:43	openspect	0	ppm			C:\Documents and Settings\UEO
14	2/14/2007 15:58	Cd	0	ppm	2.1		C:\Documents\jeo\CdD3_2.cib
15	2/14/2007 15:58	Pb	5.4	ppm	2		C:\Documents\jeo\PbD3_2.cib
16	2/14/2007 16:00	Cr	26.3	ppm	10.9		C:\Documents\jeo\CrD3_2.cib
17	2/14/2007 16:00	Br	1.6	ppm	0.8		C:\Documents\jeo\BrD3_2.cib
18	2/14/2007 15:58	Hg	6.2	ppm	3.6		C:\Documents\jeo\HgD3_2.cib
19	2/14/2007 15:56	openspect	0	ppm			C:\Documents and Settings\UEO
20	2/14/2007 16:07	Cd	133.2	ppm	5.3	NG	C:\Documents\jeo\CdD3_2.cib
21	2/14/2007 16:08	Pb	142.2	ppm	4.1	NG	C:\Documents\jeo\PbD3_2.cib
22	2/14/2007 16:09	Cr	14.6	ppm	1.7		C:\Documents\jeo\CrD3_2.cib
23	2/14/2007 16:08	Br	181.4	ppm	3.6	NG	C:\Documents\jeo\BrD3_2.cib
24	2/14/2007 16:08	Hg	1.1	ppm	2		C:\Documents\jeo\HgD3_2.cib
25	2/14/2007 16:05	openspect	0	ppm			C:\Documents and Settings\UEO

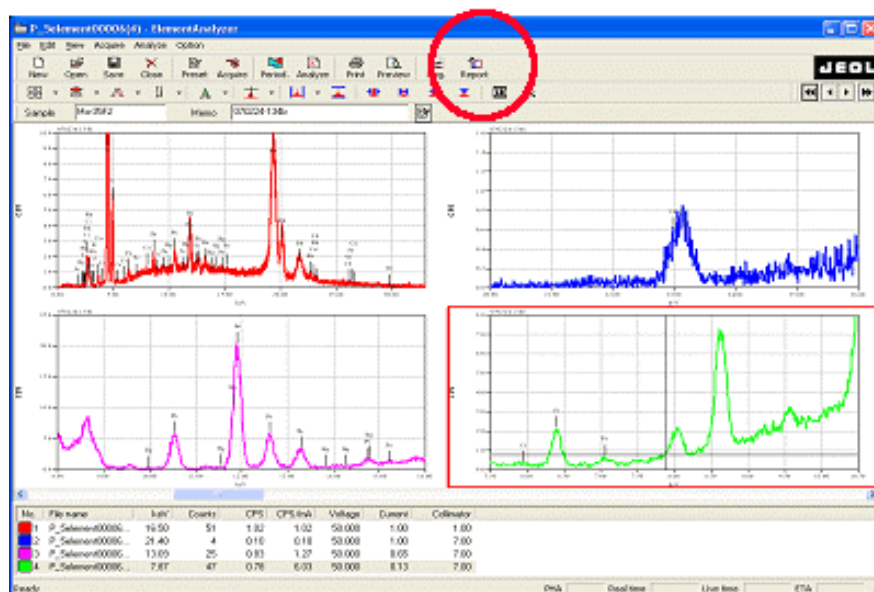
Analytical Results

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Documentation

1. Analytical results



2. Data selection

3. Complete analytical report

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Major accessories

1. Specimen observation device (CCD camera)

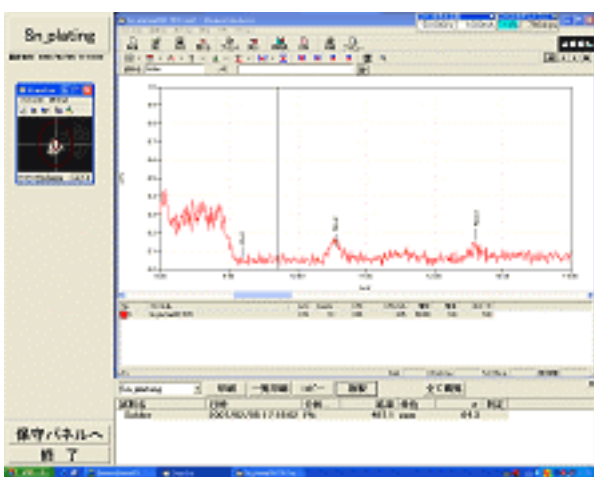
A combination of CCD camera and illumination device for sample observation and image acquisition



2. Tin (Xn) plate software (new)

Software designed to screen Pb in lead free solder plates (Sn alloy)

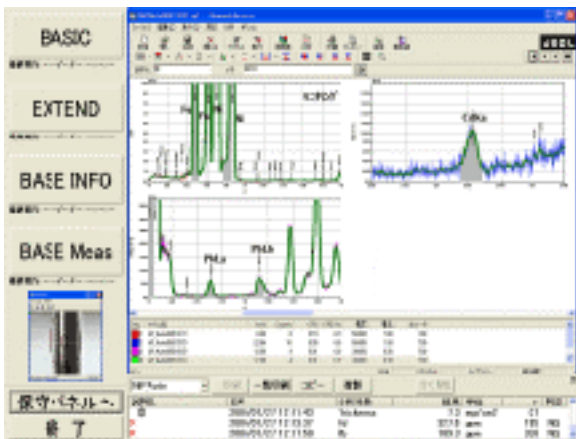
- Pb in lead-free solder plate is difficult to analyze due to the effect from the thickness of the plating layer.
- Automatically corrects the thickness and size of the plating layer, enabling screening of Pb in the plate sample.



3. Nickel (Ni) plate software (new)

Software designed to screen Pb and Cd in Ni plates

- Automatically corrects sample thickness/size.
- Identifies the substrate, and corrects its effect on Pb analysis.



4. Prolen 426

Thin round film for sample adjustment; 500 sheet/package

- For analysis of liquid, powder, and trace samples



5. Sample receptacle

Double open sample receptacle, 100 pieces/package

- For analysis of liquid, powder, and trace samples



6. 16 piece auto sample exchanger (Factory option)

For continuous analysis of up to 16 samples



7. Vacuum unit (Factory option)

For evacuation of specimen chamber to enhance light element sensitivity

JSX-3400R



8. Dewar DC-10

10 liter liquid nitrogen container



Specifications

JSX-3400R

Element range	Na-U
X-ray bulb	Rh target, 5 to 50 kV, 1 mA, 50 W
Filter	Auto exchange of 4 filters (including Open)
Collimator	1 mm ϕ , 3 mm ϕ , 7 mm ϕ (RhOS: 7 mm ϕ)
Detector	Liquid nitrogen cooling Si (Li) semiconductor detector
Liquid nitrogen	3 lit Dewar (consumption 1 lit/day or less), used only during analysis
Specimen chamber	300 mm ϕ x 150 mmH, atmosphere (vacuum optionally available)
PC	Windows [®] XP, liquid crystal display, color printer
Data processor	RoHS analysis (plastic, metals, documentation), general analysis
Calibration samples	For routine check, energy and peak calibration
Power supply	Single phase AC100 V \pm 10%, 15 A, Type D